


<b>Search Notes</b>  	<b>Application/Control No.</b>  10517917	<b>Applicant(s)/Patent Under Reexamination</b>  MARTENS ET AL.
	<b>Examiner</b>  Heyi, Henok G	<b>Art Unit</b>  2609

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Searched three different classes by combining with text search. I also used the international search report to reject all claims.	07/12/07	Henok Heyi
369/94, 275.4, 288 (text search only - see the search history printout)	07/12/07	Henok Heyi
Updated search and consulted with Primary Wayne Young.	07/03/2008	Henok Heyi
Updated search.	04/10/2009	Henok Heyi

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/HENOK G HEYI/  
Examiner, Art Unit 2627